ETX-A55E

Temperature/Humidity Test Report

Report NO: 15E090030

Test Cause
For ATRF No. TS150615 Request

Summary	☐ **Pass** ☐ **Fail** Note : There is/are ___ defect(s) not list in the report, please check it in the DTS Website. ☑ **Pass with Deviation** **Comment:** We found the COM Port 2 error for run temperature variation operation test with Burn In Test When Burn In Test with COM Ports speed performance is set on 115200Kbits/Sec. So, we changed the original COM Ports speed performance 115200Kbits/Sec change to 9600 Kbits/Sec and then run temperature variation operation test with Burn In Test again, can be to get COM ports pass.

Issue date	Approval	Test Engineer
2015-07-16	**KJ Wang**	**Jerry Chen**

Test item list

Testing Result

Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	
2	Temperature variation operation test	Pass	
3	Cold start and hot start test	Pass	

Configuration of EUT

Test Product: ETX-A55E A0.3

Sample Configuration & Quantity Under Test:

1. M/B Name: CPU Board: TEX-A55E Rev. A0.3 & Carrier Board: ECB-902M Rev A1.0

2. CPU: AMD G-T56N 1.65GHz

3.North Bridge: AMD G-Series (T56N)

4.South Bridge: AMD FCH/A55E

5. BIOS Ver.: ETX-A55E R0.6 (YHD5AM06) (06/27/2015)

6. Memory: Transcend DDR3L 1600 8GB / SEC (K4B4G0846D)

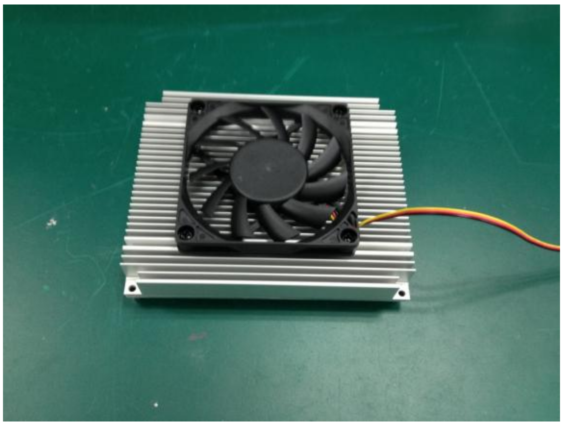
7. **USB Flash:** Transcend 4GB (For DOS Mode Power On/Off Test)

8. 2.5“ SATA HDD: WD / WD10JPVX 1TB

9. Test Software: Windows 8 / Run PassMark Burn In Test 8.0 Pro

10. ATX Power: CWT / DSA400P-C

11. Photos:



Temp./humidity power on/off test

Test Date: 07-13 ~ 14-2015

Test Site: AAEON QE Dept.

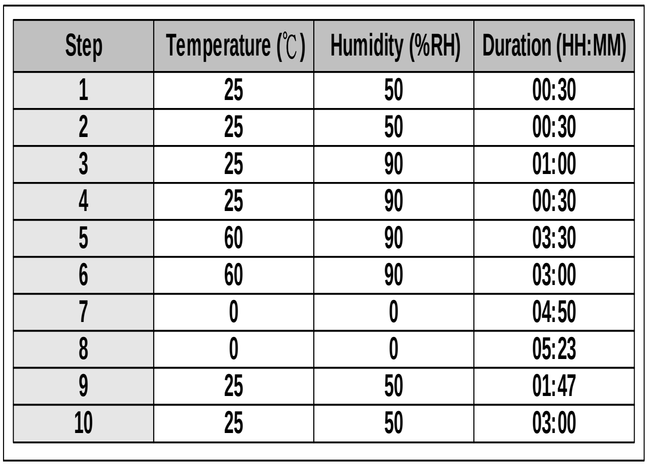
Test Standard: Refer to IEC 68-2-30 Testing procedures
Test Db: Damp Heat Test

Test Equipment:

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)
Model: THS-D7TS-100+LN2
Date of Calibration: 09/11/14
Serial Number: A0004

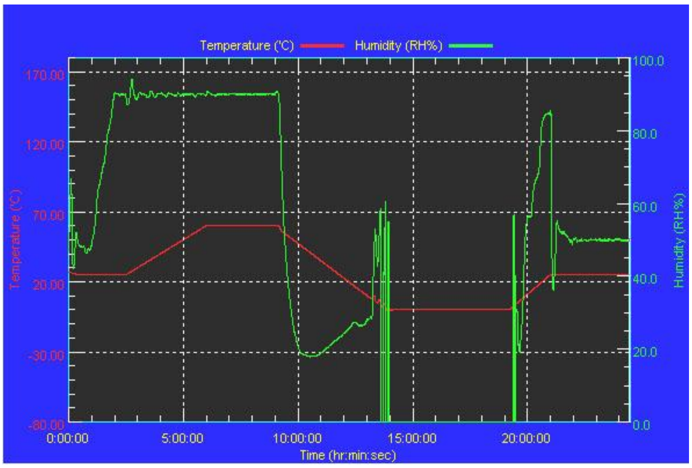
Temperature & Humidity Power On/Off Test:

Testing Specification:



Step	Temperature (℃)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

Test Curve:



Test Result:

Test Method	Actual	Successful	Failure rate
Power On/Off	1120/times	1120/times	0 %
Note: Failure rate need to under 0%.			

Temperature variation operation test

Test Date: 07-15 ~ 16-2015

Test Site: AAEON QE Dept.

Test Standard: Refer to IEC 68-2-14 Testing procedures

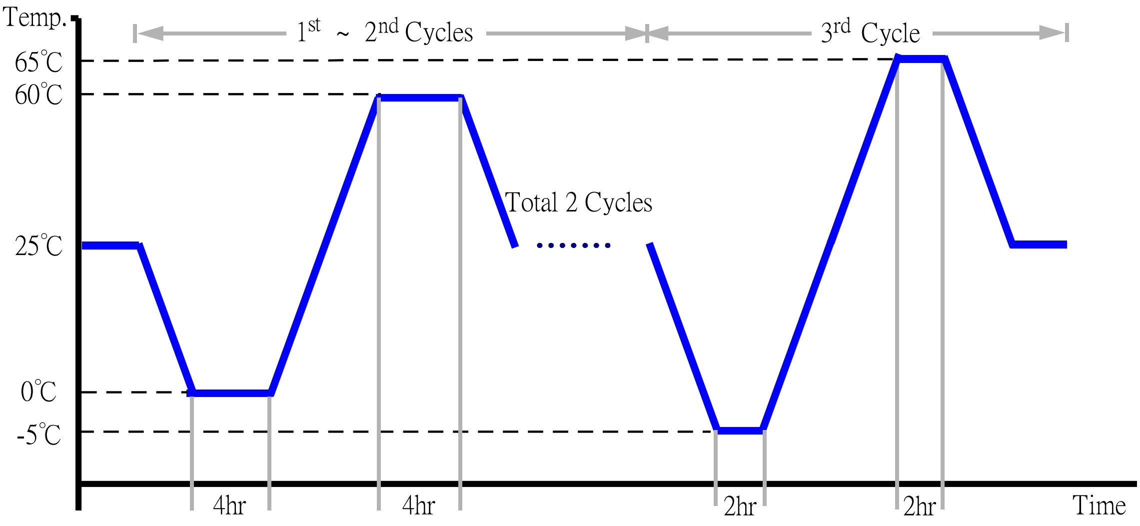
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)
Model: THS-D7TS-100+LN2
Date of Calibration: 09/11/14
Serial Number: A0004

Temperature & Humidity Cycle Test:

1. Test Low Temperature: 0℃ (1~2 cycles)
   -5℃ (3rd cycle)
2. Test High Temperature: 60℃ (1~2 cycles)
   65℃ (3rd cycle)
3. Test dwell time: 4Hrs (1~2 cycles)
   2Hrs (3rd cycle)
4. Temperature slope: 2℃/min
5. Test cycle: 3 cycles
6. Test Environment Curve:



Test Result:

No issues were found during the temperature variation operation test.

Cold start and hot start test

Test Date: 07-14 ~ 15-2015

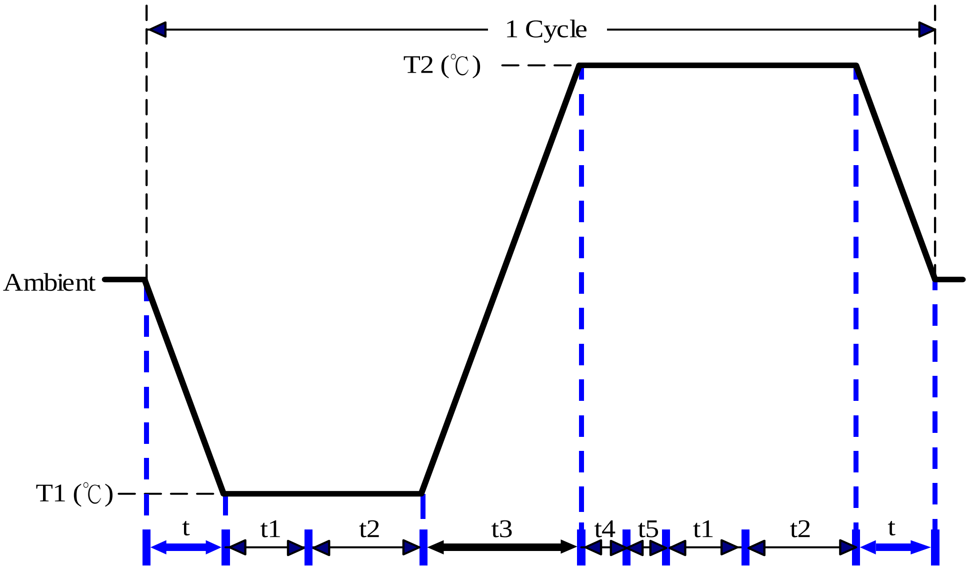
Test Site: AAEON QE Dept.

Test Standard: Refer to IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber: (K.SON. INS. TECH. CORP.)
Model: THS-D7TS-100+LN2
Date of Calibration: 09/11/14
Serial Number: A0004

Test Condition:



Parameters	Description
T1	-5℃
T2	65℃
t1	1 hrs
t2	2 hrs
t4, t5	30 min
t, t3	2℃/min
n (Cycle)	1

t,t3 = temprature slope
t, t1: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)
t3,t4: Run PassMark Burn In Test
t5: Windows 8 Software restart test 2 times
Test Software:Windows 8

Test Result:

a. No issues were found during the cold start test.
b. No issues were found during the hot start test.